

MATERIALS THAT MATTER

Laser Diode Assembly from Single Emitter VCSEL to High Power Laser Bars

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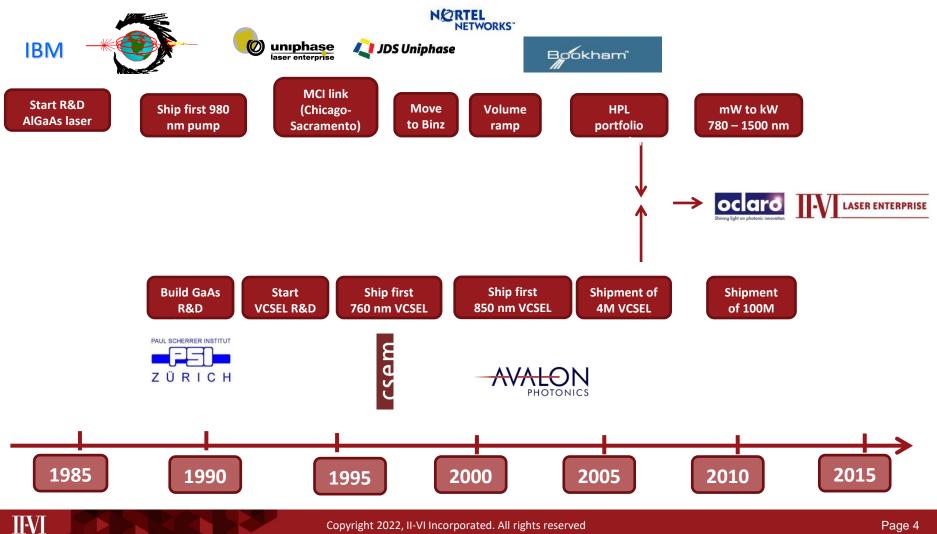
Outline

- 1. Who is II-VI Laser Enterprise?
 - a. II-VI company overview
 - b. History of Laser Enterprise
 - c. Overview of products
- 2. Single Emitter VCSEL for Data Center
- 3. Multi Emitter VCSEL for 3D-Sensing
- 4. Single Edge Emitter for Pump Lasers for Amplifier in Telco
- 5. Single Edge Emitter as Pump Lasers for Fiber Laser in Industry
- 6. Multi Edge Emitter for Welding in Industry, High Power Laser Bars
- 7. Testing and BI of components
- 8. Reliability of Telco Pump Lasers

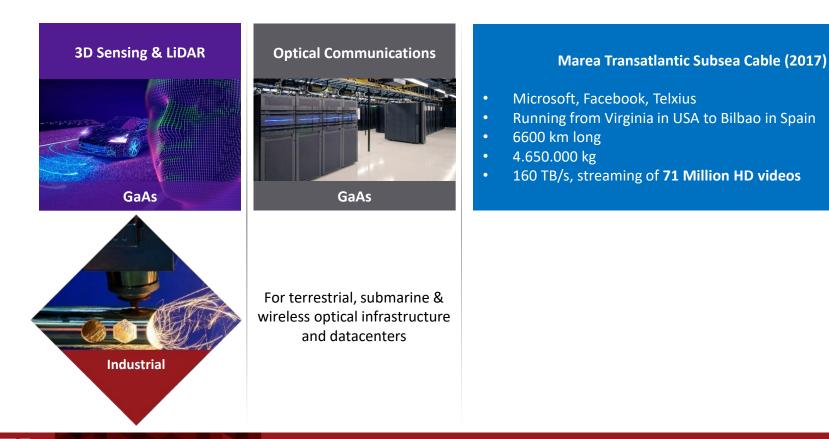
Global Footprint II-VI

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Addressing Multiple Strong and Growing Markets



II-VI

II-VI Laser Enterprise





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Zürich:

- 11'000 m²
- 350 employees
- Epitaxy: MBE, MOVPE
- Waferfab
- Bar/Chip-Line
- Assembly and Test
- R&D

Philippines:

- 1′300 m2
- 80 employees
- Assembly and Test

Assembly Lines in Zurich and Calamba



Die Bonder:

10 x Micron 2 (ESEC) for p-up 1 x FC 250 (SET) for p-up and p-down 1 x Palomar 3800 for p-down 1 x Palomar 6500 for p-down 2 x Infotech IP-600 for p-up and p-down 1 x Datacon 2200 evo for PnP and p-up 2 x ATV SRO ovens for manual assemblies



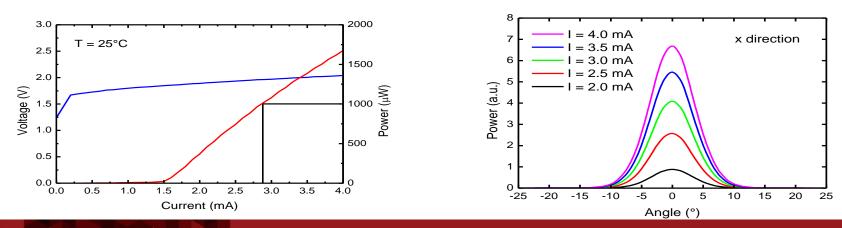
Wire Bonder: 2 x G4 Delvotec 3 x G5 Delvotec 1 x Palomar 8000

VCSEL for Computer Mouse and Data Center

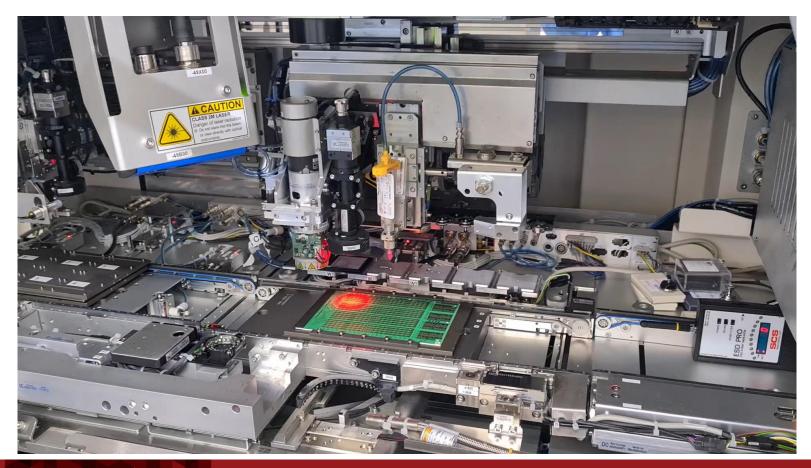


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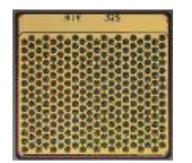
- Vertical Surface Emitting Laser
- Size: 150 micron x 100 micron
- Power: > 1 mW, Single Gaussian mode emission for computer mouse
- Shipment to customers as KGD typically on frame
- Assembly only for lot validation, wafer release and reliability tests on test boards
- Die Bonding using Ag-Epoxy



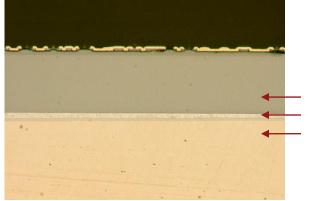
Die Bonding of Single Emitter VCSEL using Datacon



Multi Emitter VCSEL for 3D Sensing



- Size: 1 mm x 1 mm
- Power: > 2 W
- Shipment to customers as KGD typically on frame
- Assembly only for lot validation, wafer release and reliability tests on test substrate
- Die Bonding using AuSn Soldering or pressure less Ag-Sintering

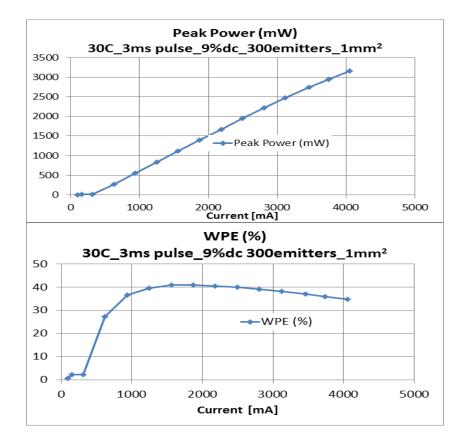


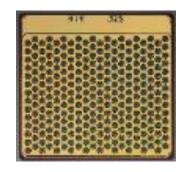
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Cross section of Multi Emitter VCSEL using Ag Sintering

Laser Die
 Silver Sintered Interface
 Test Substrate

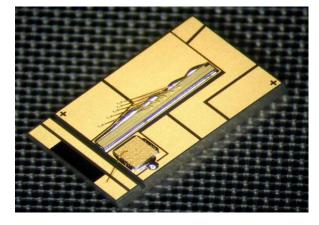
Multi Emitter VCSEL arrays





- Arrays scalable
- > 2W output power pulsed
- High efficiency (up to 40%)

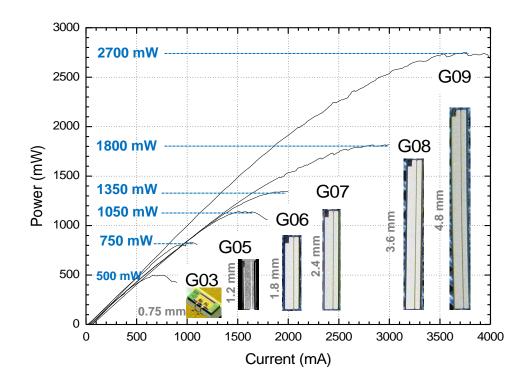
Single Edge Emitter for Telco Pump Applications



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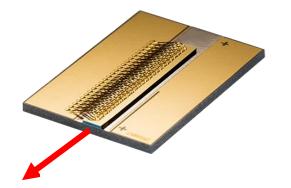
- Single Edge Emitter
- Size: 400 micron x 3600/4800 micron
- Power: 200 600 mW as Single Chip Package
- Power: 400 1000 mW as Dual Chip Package
- Shipment to internal customers on substrate (Chip on Carrier) incl. thermistor and optional photo diode for fiber coupling and module building (1 000 000 per year)
- Die Bonding using AuSn solder preforms

980-nm Pump Laser Generations G0x (1998 - 2021)

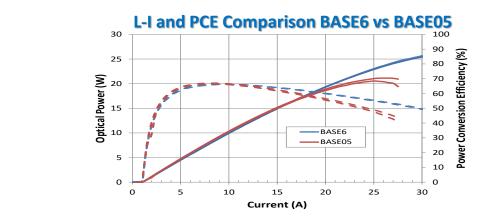




Single Edge Emitter as Pump Lasers for Fiber Lasers



- High Power Single Emitter
- Size: 0.4 mm x 3.6 mm
- Power: > 20 W
- Shipment to customers as KGD typically on frame or as Chip on Submount (CoS) and on C-Mount
- P-Down Die Bonding using AuSn solder





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Flip Chip Bonding of CoS



Multi Edge Emitter for Welding



- High Power Laser Bar
- Size: 10 mm x 3.6 mm, approx. 20 Emitter
- Power: 80 250 W per bar
- Shipment to internal and external customers on passive or active Cu Cooler (25 000 per year)
- Die Bonding using Soldering (AuSn, SnAgCu, SnInAg)



II-V

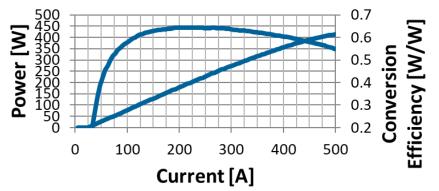
 Customers doing integration of stacking, optics, fiber coupling etc..

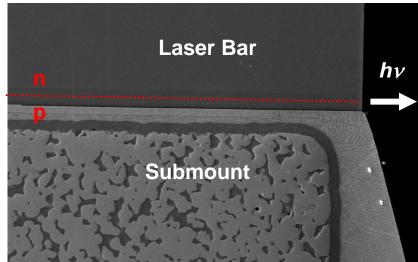
Multi Edge Emitter for Welding

Assembly Specification:

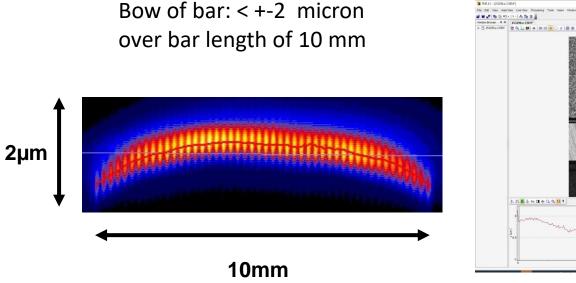
- P-down Bonding
- Alignment to Cooler
 Edge depending on
 Edge Quality (Direct
 Bonding or using
 Submount)
- Assembly Height limited to optimized Pitch for Stacking => Brightness

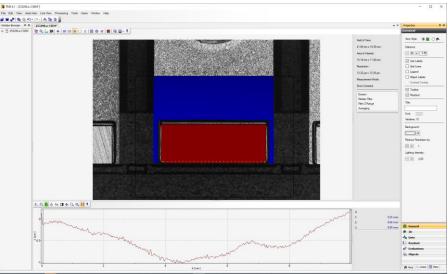
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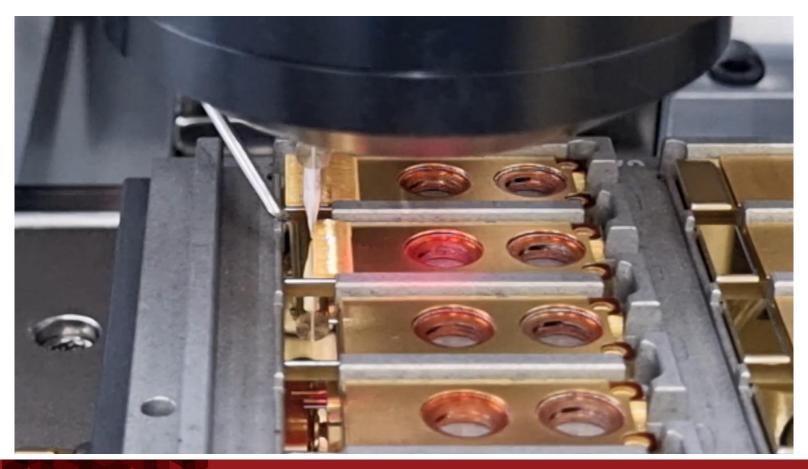
Multi Edge Emitter for Welding





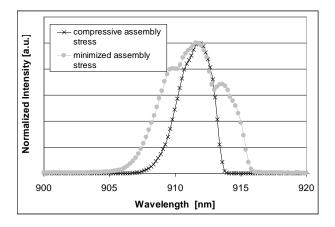
White Light Interferometer for Bow Measurement

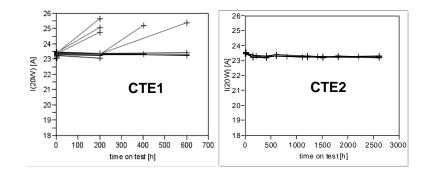
Wire Bonding of Laser Bar



Influence of Assembly Stress

- Impact of assembly stress on performance and reliability depends on chip design
- Assembly stress minimization not always preferred solution
- Design rules established based on:
 - Laser and assembly (FEM simulations)
 - Experiments
- Impact of Assembly stress on smile (curvature of emission line) => Can be partly compensated by assembly process





Spectrum of devices with same chip design, but different assembly stress

Split lot life tests of devices assembled on same type of Cu cooler using submounts with different CTEs



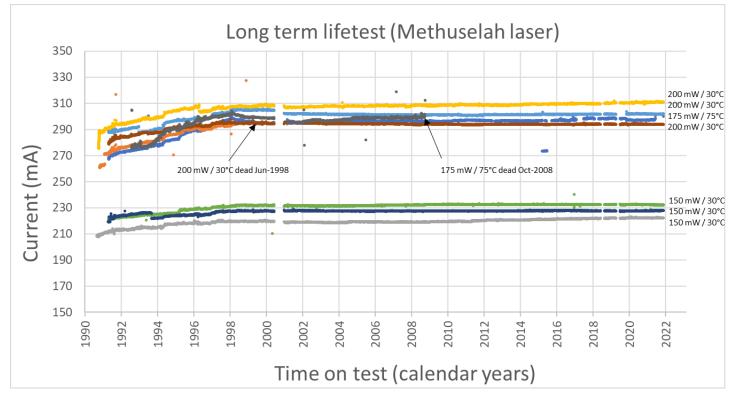
Testing and Burn In Systems



- Equipment
 Engineering for Tester and BI-systems
 inhouse, building all
 testers by ourself
- 15 000 Burn In Slots for Telco Pump Lasers in Zurich



Reliability of Telco Pump Lasers



Depending on Conditions accelerated lifetime 91 – 2580 years

Thank You!

- Dr. Michael Moser
- Dr. Tomas Pliska
- Dr. Sebastian Arlt
- Goran Eskic
- Dominik Hälg
- Dr. Brigitte Ketterer
- Franco Marandino
- Javier Moizello
- Dr. Rokhaya Müller
- Daniel Sticherling

We are hiring !



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